

## 향상된 고체 유전체로서 폴리이미드/알루미나 복합재 필름의 제조 및 분석

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## Preparation and Characterization of Polyimide/Alumina Composite Films as Improved Solid Dielectrics

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**Abstract:** Polyimide/alumina (PI/Al<sub>2</sub>O<sub>3</sub>) nanocomposite films were prepared by incorporating different nano-sized Al<sub>2</sub>O<sub>3</sub> contents into PI which derived from pyromellitic dianhydride (PMDA) and a flexible diamine 4,4-bis(3-aminophenoxy)biphenyl (4,3-BAPOBP). The micromorphology, chemical structure, dielectric, mechanical properties and glass transition temperatures ( $T_g$ ) of prepared films were investigated by scanning electron microscopy (SEM), Fourier transform infrared spectroscopy (FTIR), X-ray diffraction (XRD), LCR metry, electronic tensile testing and differential scanning calorimetry (DSC). SEM images show uniform distribution of Al<sub>2</sub>O<sub>3</sub> nanoparticles in matrix. FTIR spectra indicate that Al<sub>2</sub>O<sub>3</sub> nanoparticles are functionalized with  $\gamma$ -aminopropyl triethoxysilane ( $\gamma$ -APS) and the imidization was complete. XRD patterns reveal the peaks of PI/Al<sub>2</sub>O<sub>3</sub> composite films were similar to those of Al<sub>2</sub>O<sub>3</sub>, indicating that the crystal structure of Al<sub>2</sub>O<sub>3</sub> remains unchanged and stable after being doped into PI matrix. Meanwhile, the effects of additives on the dielectric and mechanical properties of composite films were also studied. The results show the dielectric constant and dielectric loss of hybrid materials increase with the addition of Al<sub>2</sub>O<sub>3</sub> nanoparticles. The electrical breakdown strength and tensile strength of PI/Al<sub>2</sub>O<sub>3</sub> can be markedly improved by the addition of appropriate amounts of Al<sub>2</sub>O<sub>3</sub> to the PI matrix.

**Keywords:** polyimide, alumina, nanocomposite films, dielectric properties, mechanical properties.

### Introduction

Recently, with the advances of high technology industries, the developments of insulating materials with high temperature durability and good mechanical properties are to be required.<sup>1-3</sup> Large demand for the solid thin-film dielectrics with high dielectric constants especially for use in the fabrication of high end capacitors has been stated in the literatures.<sup>4-6</sup> Among various organic polymers, the polyimide (PI) has been paid a lot of attention due to excellent dielectric properties, attractive

mechanical properties, and outstanding thermal stability, which have been extensively applied in terms of the dielectric and microelectronic industry.<sup>1</sup> However, it is proved that neat PI cannot still meet the ever-growing demand of electrical insulation systems. To enhance dielectric performance including dielectric constant and dielectric loss, many research groups devoted oneself to developing PI/inorganic hybrids by embedding inorganic particles having high dielectric constant into PI matrix, such as PI/SiO<sub>2</sub>,<sup>7-9</sup> PI/TiO<sub>2</sub>,<sup>10,11</sup> PI/SiC,<sup>12,13</sup> PI/BaTiO<sub>3</sub>,<sup>14-16</sup> *et al.* Among the inorganic fillers available commercially, alumina (Al<sub>2</sub>O<sub>3</sub>) is more usually employed to improve dielectric properties of the matrix because it possesses superior insulating qualities, higher constant (around 8-10) and high thermal conductivity.<sup>17-19</sup> Therefore, combination of Al<sub>2</sub>O<sub>3</sub> and PI

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would be a good choice for the above mentioned polymer/inorganic composite.<sup>16</sup> According to Alias *et al.*,<sup>18</sup> the dielectric constant value of PI/Al<sub>2</sub>O<sub>3</sub> composite increased to 3.5 with the addition of 10 wt% Al<sub>2</sub>O<sub>3</sub> content compared with the obtained neat PI film, which reflected a dielectric constant of 3 when measured at 10<sup>6</sup> Hz. As reported by Li *et al.*,<sup>19</sup> a slight change in dielectric constant value was observed after Al<sub>2</sub>O<sub>3</sub> was incorporated into PI.

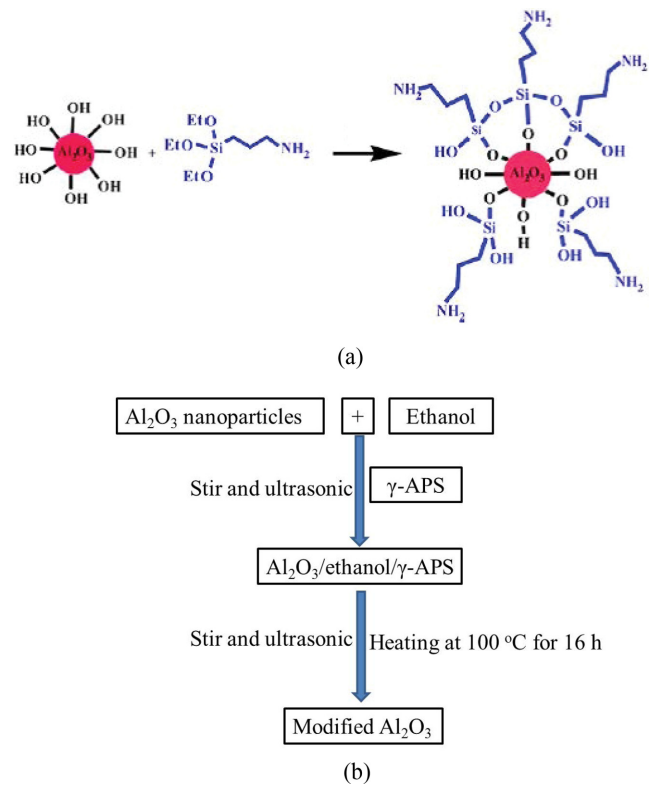
Noticeably, in processing the organic/inorganic nanocomposites, the degree of dispersion of the inorganic nanoparticles is of great importance because it determines the desired properties of the prepared composites. To overcome dispersion issues, various types of organosilane are usually used as coupling agents where the organic part is supposed to interact with the polymer chain and alkoxy units on the other hand the inorganic nanoparticles. Thus, the compatibility between these two phases will be improved.

In this paper, the PI/Al<sub>2</sub>O<sub>3</sub> composite films with different amounts of Al<sub>2</sub>O<sub>3</sub> were prepared to obtain a much higher increment in dielectric and mechanical properties via *situ* polymerizing. PI which was used as matrix for preparation of nanocomposites was prepared by pyromellitic dianhydride (PMDA) and 4,4-bis(3-aminophenoxy)biphenyl (4,3-BAPOBP). Meanwhile, Al<sub>2</sub>O<sub>3</sub> nanoparticles were modified with  $\gamma$ -APS to introduce organic functional groups on the surface of Al<sub>2</sub>O<sub>3</sub>. The microstructure of the composite films was characterized by SEM, FTIR and XRD. The dielectric and mechanical properties changes were also evaluated and discussed.

## Experimental

**Materials and Reagents.** Pyromellitic dianhydride (PMDA, 98.5%) was obtained from Sinopharm Chemical Reagent Co., Ltd, China and dried at 130 °C for 3 h before use. 4,4-bis(3-aminophenoxy)biphenyl (4,3-BAPOBP, 98%,) was supplied by Heowns Biochemical Technology Co., Ltd, China and used directly as received. *N,N*-dimethylacetamide (DMAc, 99.5%) was purchased from Shanghai SSS Reagent Co., Ltd, China and purified by distillation under reduced pressure and stored over 4 Å molecular sieves prior to use. The Al<sub>2</sub>O<sub>3</sub> nanoparticle was obtained from Guangzhou GBS High-tech & Industry Co., Ltd, China and used as received.  $\gamma$ -Aminopropyl triethoxysilane ( $\gamma$ -APS) were purchased from Nanjing Shuguang Chemical Plant and used directly as received.

**Preparation of PI/Al<sub>2</sub>O<sub>3</sub> Composite Films.** Herein, Al<sub>2</sub>O<sub>3</sub> nanoparticle was treated with  $\gamma$ -APS because the organic



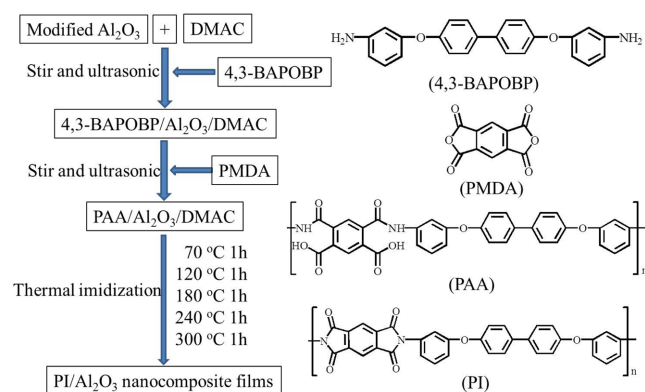
**Figure 1.** (a) Modification of Al<sub>2</sub>O<sub>3</sub> nanoparticles with  $\gamma$ -APS<sup>20</sup>; (b) schematic representation of modified Al<sub>2</sub>O<sub>3</sub> preparation.

chains of  $\gamma$ -APS can fulfil steric hindrance between inorganic nanoparticles and prevent their aggregation (Figure 1). In modified Al<sub>2</sub>O<sub>3</sub>, hydroxyl groups on the surface of Al<sub>2</sub>O<sub>3</sub> react with  $\gamma$ -APS to form Al–O–Si bonds.<sup>20</sup>

The preparation flow of modified Al<sub>2</sub>O<sub>3</sub> is as follows: Al<sub>2</sub>O<sub>3</sub> nanoparticles were firstly dissolved in ethanol absolute, and then heated up in a water bath of 70–75 °C, and 4 wt% content of coupling agent was added with the treatment of ultrasonic wave. The mixture was stirred mechanically again for 4 h, followed by heating at 100 °C for 16 h to induce further reaction of  $\gamma$ -APS with -OH groups existing on the surfaces of Al<sub>2</sub>O<sub>3</sub> particles, and then abraded to use.<sup>21</sup>

In order to study the effect of Al<sub>2</sub>O<sub>3</sub> inorganic nanoparticle on dielectric, mechanical and thermal properties of composite films, a number of PI/Al<sub>2</sub>O<sub>3</sub> composites were prepared with 0, 2, 4, 6, 8 and 10 wt% inorganic nanoparticle doping. The schematic representation of the preparation flow of PI/Al<sub>2</sub>O<sub>3</sub> composite films is shown in Figure 2.

A typical synthesis of polyamide acid/Al<sub>2</sub>O<sub>3</sub> (PAA/Al<sub>2</sub>O<sub>3</sub>) is as follows that a calculated quantity of modified Al<sub>2</sub>O<sub>3</sub> nanoparticles with  $\gamma$ -APS content 4 wt% was added in fresh purified DMAc with the aid of ultrasonic wave and stir. After



**Figure 2.** Schematic representation of PI/Al<sub>2</sub>O<sub>3</sub> nanocomposite film preparation.

a stable suspension was obtained, 4,3-BAPOBP was added to this solution. The ultrasonic wave and stir were simultaneously used until the 4,3-BAPOBP was completely dissolved. Then PMDA was added to this solution with a certain time sequence, and the mixture was stirred mechanically again for 8 h to get a homogeneous PAA/Al<sub>2</sub>O<sub>3</sub> solution.<sup>21,22</sup>

The PAA/Al<sub>2</sub>O<sub>3</sub> solution was casted onto the clear glass plate to form films that were then placed in a vacuum oven for 20 min to remove air bubbles. The films were then heated successively at 70, 120, 180, 240 and 300 °C for 1 h, respectively. Finally, they were cooled to room temperature, immersed in distilled water for 2 h, and then removed from the glass plates using a razor blade.<sup>8,9</sup>

**Characterization. Scanning Electron Microscopy (SEM):** Rectangular specimen (5 mm×5 mm) surfaces were sputter coated with gold and then observed with by Carl Zeiss Evo-50 scanning electron microscopy.

**Fourier Transform Infrared (FTIR):** FTIR spectroscopic analysis of Al<sub>2</sub>O<sub>3</sub> nanoparticles and PI/Al<sub>2</sub>O<sub>3</sub> composite films

was conducted on a Nicolet Magna 750 FTIR spectrophotometer at a wavelength ranging from 400 to 4000 cm<sup>-1</sup>.

**X-ray Diffraction (XRD):** XRD was carried out on the neat PI, Al<sub>2</sub>O<sub>3</sub> nanoparticles, PI/Al<sub>2</sub>O<sub>3</sub> composite films using a Bruker AXS D8 diffract meter at a 2θ angle of 10-75°.

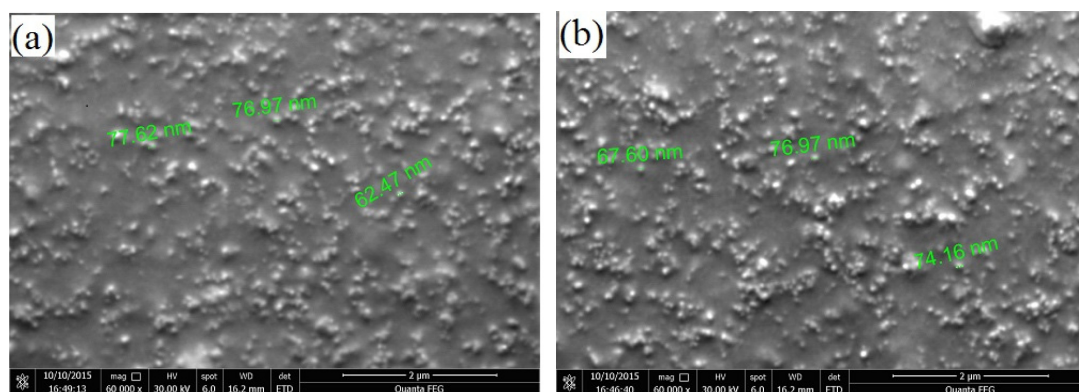
**Measurement of Dielectric Properties:** The electrical breakdown strength was measured by a voltage with two copper electrodes immersed in silicone oil. In the process, the samples were cut to dimensions of 30 mm×30 mm and the voltage was raised with a rate of 1 kV s<sup>-1</sup> while dielectric constant and dielectric loss were measured on an Agilent LCR meter.

**Measurement of Mechanical Properties:** To estimate the mechanical properties of the PI/Al<sub>2</sub>O<sub>3</sub> composite films, tensile tests were carried out at room temperature on an electronic tensile testing machine (SANS Power Test v3.0, Shenzhen SANS Material Test Instrument Co., Ltd, China). Both the tensile strength and the elongation at break were recorded during the experiment.

**Differential Scanning Calorimeter (DSC) Measurements:** The glass transition temperatures (*T<sub>g</sub>*) of the composite films were determined by DSC (Mettler Toledo DSC1, USA) in a nitrogen atmosphere. The samples were heated from 0 to 400 °C followed by a cooling cycle. Both the heating and cooling rates were 15 °C min<sup>-1</sup>.

## Results and Discussion

**Microstructure Analysis.** SEM was performed to observe and investigate the surface morphology of the PI/Al<sub>2</sub>O<sub>3</sub> composites. According to Figure 3, the inorganic particles are uniform distribution and no obvious aggregation in the matrix. The distribution becomes more packed with the increment of

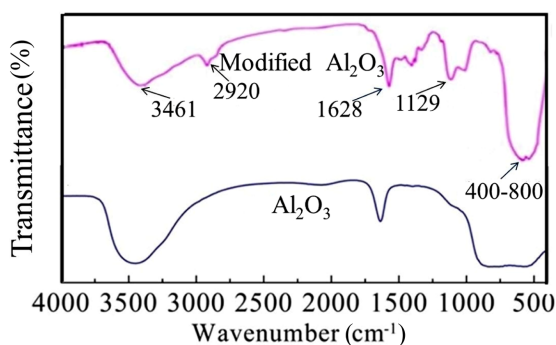


**Figure 3.** SEM surface images of PI/Al<sub>2</sub>O<sub>3</sub> nanocomposite films with different Al<sub>2</sub>O<sub>3</sub> contents: 8 wt% (a); 10 wt% (b).

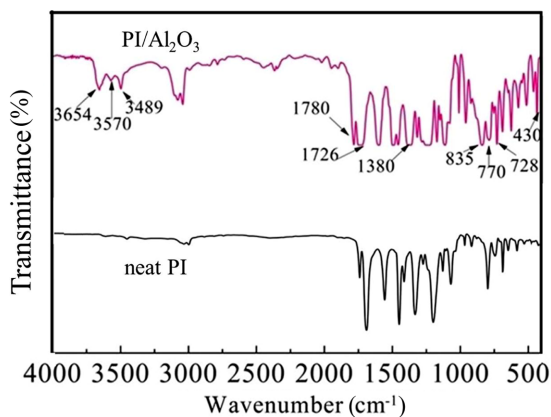
$\text{Al}_2\text{O}_3$  content and the particles size is about 60-80 nm, which indicates the agglomerations of nano- $\text{Al}_2\text{O}_3$  have been broken into basic particles. The interfacial bonding between the  $\text{Al}_2\text{O}_3$  particles and the PI matrix are considerably good. The result is due to coupling agent, the ultrasonic action and the mechanical stirring.<sup>18</sup>

FTIR spectroscopy was carried out to study the chemical structures of  $\text{Al}_2\text{O}_3$  particles, neat PI and PI/ $\text{Al}_2\text{O}_3$  composites. FTIR spectra of  $\text{Al}_2\text{O}_3$  and modified  $\text{Al}_2\text{O}_3$  are exhibited in Figure 4. It can be clearly seen that the broad absorption peak from 400 to 800  $\text{cm}^{-1}$  is due to the characteristic absorption band of  $\text{Al}_2\text{O}_3$ . The bands at 1129 and 1628  $\text{cm}^{-1}$  appear in the spectra of  $\gamma$ -APS modified  $\text{Al}_2\text{O}_3$  resulting from the stretching of Si-O bond and N-H bond. FTIR spectrum of functionalized  $\text{Al}_2\text{O}_3$  with  $\gamma$ -APS gave a broad absorption band located at 3461  $\text{cm}^{-1}$ , which is attributed to -OH and - $\text{NH}_2$  groups.<sup>20</sup> The peak at 2920  $\text{cm}^{-1}$  can be assigned to the symmetric methylene stretching (- $\text{CH}_2$ ). Based on the above result of analysis, it is confirmed that coupling agents have been successfully grafted onto the surface of  $\text{Al}_2\text{O}_3$  particles.<sup>16,19</sup>

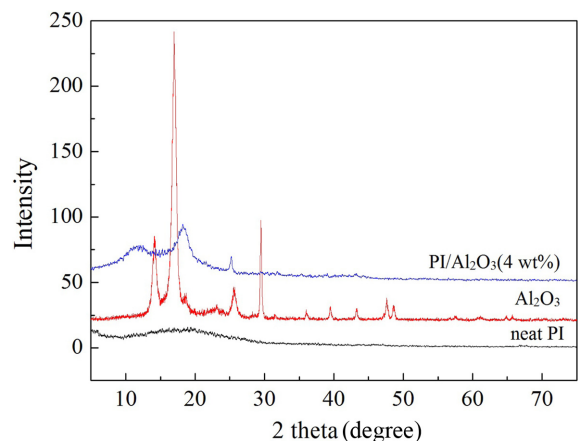
In Figure 5, the characteristic peaks of imide group are



**Figure 4.** FTIR spectra of  $\text{Al}_2\text{O}_3$  and modified  $\text{Al}_2\text{O}_3$ .



**Figure 5.** FTIR spectra of neat PI and PI/ $\text{Al}_2\text{O}_3$  nanocomposite film.

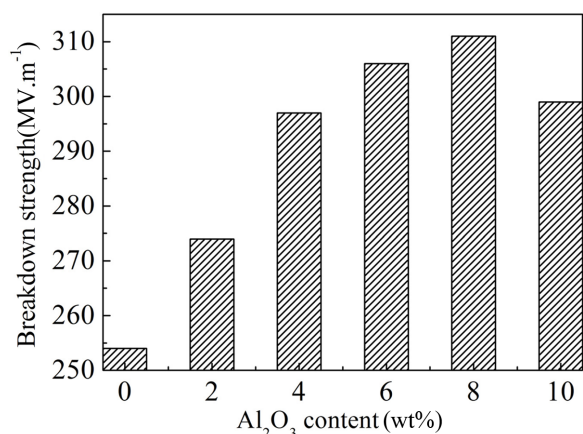


**Figure 6.** XRD patterns of neat PI,  $\text{Al}_2\text{O}_3$  nanoparticle and PI/ $\text{Al}_2\text{O}_3$  4 wt% loading nanocomposite film.

observed at 1726  $\text{cm}^{-1}$  (C=O symmetric stretching), 1780  $\text{cm}^{-1}$  (C=O asymmetric stretching), 3489  $\text{cm}^{-1}$  (C=O imide overtone band), 728  $\text{cm}^{-1}$  (C=O bending vibration) and 1380  $\text{cm}^{-1}$  and 3570  $\text{cm}^{-1}$  (C-N stretching).<sup>21</sup> The peak at 3654  $\text{cm}^{-1}$  may be due to hydroxyl groups (-OH) on the surface. We find also that, there is no absorption near 1650  $\text{cm}^{-1}$ , which shows that PAA has been completely imidized. Moreover, the peaks at 835, 770 and 430  $\text{cm}^{-1}$  are assigned to Al-O-Al bonds.<sup>19,20</sup> These results indicate the complete imidization of hybrid films, the successful preparation of PI/ $\text{Al}_2\text{O}_3$  hybrid films and the imidization process has not been impeded by inorganic particles.<sup>20</sup> The presence of  $\text{Al}_2\text{O}_3$  was further confirmed by performing an XRD test.

The crystallinity of the PI/ $\text{Al}_2\text{O}_3$  composite films was studied via the XRD test. The XRD pattern of PI shown in Figure 6 displays a broad peak with  $2\theta$  centered at around  $18^\circ$ , revealing that the PI molecules have an amorphous structure. Meanwhile, in the PI/ $\text{Al}_2\text{O}_3$  composite films, the diffraction peaks of  $\text{Al}_2\text{O}_3$  are unchanged at  $2\theta$ , and show diffraction patterns similar to those of pure  $\text{Al}_2\text{O}_3$ . This indicates that the  $\text{Al}_2\text{O}_3$  remains stable after being doped into the PI matrix.<sup>19</sup>

**The Breakdown Strength of Nanocomposite Film.** The breakdown strength of the PI/ $\text{Al}_2\text{O}_3$  composite films as a function of the  $\text{Al}_2\text{O}_3$  loading is shown in Figure 7. For the dielectric materials, the electrical breakdown strength is a key parameter of measuring the insulating capability because breakdown would cause short circuit which could be a fatal malfunction for the power equipment.<sup>19,23</sup> According to Figure 7, all of the electrical breakdown strengths of the samples are over 250  $\text{MV m}^{-1}$ . Moreover, the electrical breakdown strengths of the films first increase and then decrease with increasing

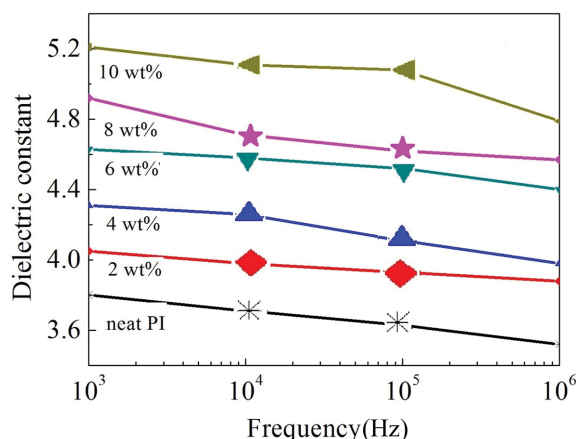


**Figure 7.** Breakdown strength of PI/Al<sub>2</sub>O<sub>3</sub> nanocomposite film vs. nano-Al<sub>2</sub>O<sub>3</sub> loading.

Al<sub>2</sub>O<sub>3</sub> content. At an Al<sub>2</sub>O<sub>3</sub> content of 8 wt%, the electrical breakdown strength reaches a maximum value of 311 MV m<sup>-1</sup>. This can be attributed to the homogeneously dispersion of Al<sub>2</sub>O<sub>3</sub> nanoparticles in the PI matrix when Al<sub>2</sub>O<sub>3</sub> content was lower. While with increasing inorganic nanoparticles content, the aggregation of excessive Al<sub>2</sub>O<sub>3</sub> fillers in organic matrix will be formed which will not only greatly decrease the interfacial areas between inorganic and organic polymer chains, but also destroy the integrity of the microstructure in the organic matrix. Thus, the movement of electrical charges through the weakest part of the testing materials is somehow allowed and the reduction of dielectric strength fluctuates.<sup>17,19</sup>

**The Dielectric Constant of Nanocomposite Film.** The dielectric constant curves of the prepared films with different Al<sub>2</sub>O<sub>3</sub> contents are depicted in Figure 8. It shows the effect of Al<sub>2</sub>O<sub>3</sub> content on the dielectric constants of PI/Al<sub>2</sub>O<sub>3</sub> composite films at the sweeping frequencies of 10<sup>3</sup>, 10<sup>4</sup>, 10<sup>5</sup> and 10<sup>6</sup> Hz. The dielectric constant varies with the sweeping frequency and Al<sub>2</sub>O<sub>3</sub> content. Generally, it decreases monotonously with sweeping frequency, due to the fact that less dipole could follow the switching field as frequency increases.<sup>18</sup>

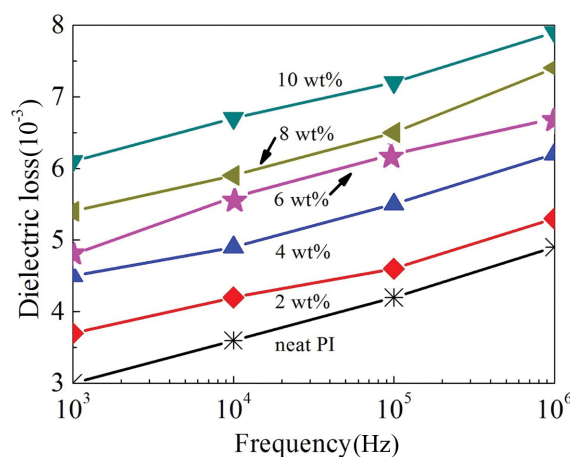
As can be seen from Figure 8, the dielectric constant performed a significant enhancement with the increase of Al<sub>2</sub>O<sub>3</sub> content. For the sample tested at the frequency of 10<sup>3</sup> Hz, the dielectric constant increased from 3.8 to 5.21 as the Al<sub>2</sub>O<sub>3</sub> content increased from 0 to 10 wt%. This improvement in dielectric constant is mainly due to the relatively high dielectric constant of Al<sub>2</sub>O<sub>3</sub> nanoparticles (8-10).<sup>24,25</sup> On the other hand, when incorporating Al<sub>2</sub>O<sub>3</sub> nanoparticles into the matrix, the free volume decreases in the matrix and the more polar groups are created. Noticeably, the number of polar groups increases



**Figure 8.** Dielectric constant of PI/Al<sub>2</sub>O<sub>3</sub> nanocomposite film vs. nano-Al<sub>2</sub>O<sub>3</sub> loading under various applied sweeping frequencies.

with the increment of the Al<sub>2</sub>O<sub>3</sub> loading, which results in further polarization and the higher dielectric constants.<sup>18,19</sup> In addition, in the PI/Al<sub>2</sub>O<sub>3</sub> composites, the loading of Al<sub>2</sub>O<sub>3</sub> induces interfacial polarization between the organic and inorganic phases. Mobile charges accumulate at the interfaces between PI matrix and Al<sub>2</sub>O<sub>3</sub> particles, and the number of the accumulating charges increases with the increment of Al<sub>2</sub>O<sub>3</sub> content, which will cause further polarization under an electric field.<sup>26</sup>

**The Dielectric Loss of Nanocomposite Film.** Figure 9 shows the effect of Al<sub>2</sub>O<sub>3</sub> content on the dielectric loss of composite films. As Al<sub>2</sub>O<sub>3</sub> doping concentration increases, the dielectric loss increases. This is due to that the mobility of polymer chains is blocked after nanoparticles are dispersed throughout the polymers.<sup>18</sup> The fraction of the space-charge



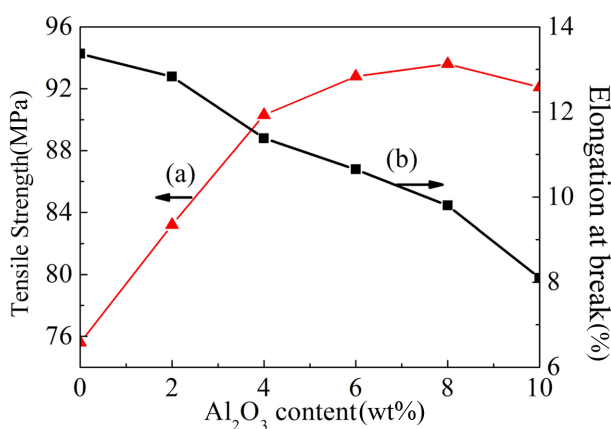
**Figure 9.** Dielectric loss of PI/Al<sub>2</sub>O<sub>3</sub> nanocomposite film vs. nano-Al<sub>2</sub>O<sub>3</sub> loading.

and dipole polarization increases under the electric fields, which accordingly increases the resistance of polymer chains relaxation and lead to the stronger dielectric loss.

Furthermore, it can also be seen that the dielectric loss increases slowly in the frequency range measured and exhibits slightly weak frequency dependence. The phenomenon is well explained by the interfacial polarization inside the composites in applied electric fields.<sup>17</sup> As the frequency increases, the interfacial polarization cannot follow the change of the used electric field; thus more energy is consumed and the dielectric loss increases.

**Mechanical Properties of Nanocomposite Film.** The tensile strength is one of the most important indicators to reflect the mechanical properties of PI/Al<sub>2</sub>O<sub>3</sub> composites. And the effect of Al<sub>2</sub>O<sub>3</sub> on tensile strength is illustrated in Figure 10(a), where each sample is characterized by tensile tests at room temperature. It can be seen that the tensile strength of the films first increases and then decreases with increasing Al<sub>2</sub>O<sub>3</sub> content. At an Al<sub>2</sub>O<sub>3</sub> content of 8 wt% the tensile strength reaches a maximum value of 93.6 MPa and shows a 23.8% increase over that of neat PI. The improvement in tensile strength is due to uniform dispersion and good interfacial adhesion between the organic and inorganic phases.<sup>27</sup> Considering the inorganic nanoparticle is the reinforcement, the tensile strength of the composites will increase. However, higher nanoparticle content leads to form more voids, which results in micro crack formation under loading, reducing the tensile strength.<sup>28</sup>

The other most important mechanical property of PI/Al<sub>2</sub>O<sub>3</sub> is the elongation at break. The relationship between tensile strength and Al<sub>2</sub>O<sub>3</sub> content is illustrated in Figure 10(b). It is found that the elongation at break of PI/Al<sub>2</sub>O<sub>3</sub> decreases with



**Figure 10.** Tensile strength and elongation at break of PI/Al<sub>2</sub>O<sub>3</sub> nanocomposite film vs. nano-Al<sub>2</sub>O<sub>3</sub> loading.

**Table 1.**  $T_g$  of PI/Al<sub>2</sub>O<sub>3</sub> Nanocomposite Films with Different Al<sub>2</sub>O<sub>3</sub> Contents

Sample	$T_g$ (°C)	Increase(°C)
Neat PI	267	-
PI/Al <sub>2</sub> O <sub>3</sub> (2 wt%)	269	2
PI/Al <sub>2</sub> O <sub>3</sub> (4 wt%)	273	6
PI/Al <sub>2</sub> O <sub>3</sub> (6 wt%)	275	8
PI/Al <sub>2</sub> O <sub>3</sub> (8 wt%)	276	9
PI/Al <sub>2</sub> O <sub>3</sub> (10 wt%)	270	3

the content of Al<sub>2</sub>O<sub>3</sub> increasing. And the elongation at break of bulk specimen without reinforcement is about 13.37%, whereas, with 10 wt% Al<sub>2</sub>O<sub>3</sub> reinforcement, the elongation at break decreases by about 39.4% than the neat matrix. This is presumably due to the network structure of hybrid films making higher cross-linking density and the stronger interaction force between molecular chains. Therefore, the toughness of the composites decreases with the Al<sub>2</sub>O<sub>3</sub> content increasing and the fracture of the composites occur earlier, leading to the lower elongation at break.<sup>29</sup>

**$T_g$  of Nanocomposite Film.** The glass transition temperatures ( $T_g$ ) of PI/Al<sub>2</sub>O<sub>3</sub> composite films are determined by DSC means and summarized in Table 1.  $T_g$  values of the composites are higher than that of neat PI film and vary between 267 and 276 °C.  $T_g$  of origin PI is 267 °C and 269, 273, 275, 276 and 270 °C for the composite contains 2, 4, 6, 8 and 10 wt% of Al<sub>2</sub>O<sub>3</sub>, respectively. According to Table 1,  $T_g$  increases slightly with increasing Al<sub>2</sub>O<sub>3</sub> content up to 8 wt% in PI chain. It might be due to that Al<sub>2</sub>O<sub>3</sub> nanoparticles possess high thermal stability. Moreover, the presence of Al<sub>2</sub>O<sub>3</sub> restrains the movement of PI main chain and more energy was consumed to initiate and continue the chain movement, therefore higher  $T_g$  is required.<sup>18,30</sup> However,  $T_g$  decreases gradually for PI/Al<sub>2</sub>O<sub>3</sub> with Al<sub>2</sub>O<sub>3</sub> content above 8 wt% because the aggregation of excessive fillers lowers the packing density in PI molecules, compatibility and rigidity in PI chain.<sup>31,32</sup>

## Conclusions

A series of PI/Al<sub>2</sub>O<sub>3</sub> nanocomposite films has been successfully prepared via a thermal imidization method. The SEM images and FTIR spectra show that modified Al<sub>2</sub>O<sub>3</sub> nanoparticles are well dispersed in matrix and the PAA has been completely converted to PI at 300 °C. Due to the elevated structures and homogeneous distribution of Al<sub>2</sub>O<sub>3</sub> inorganic nanopar-

ticles in the matrix, the composites show good dielectric and mechanical properties. Dielectric constant and dielectric loss of the composite films increases with Al<sub>2</sub>O<sub>3</sub> nanoparticle content. Herein, the dielectric constant increases from 3.8 to 5.21 with only 10 wt% Al<sub>2</sub>O<sub>3</sub> loading at a sweep frequency of 10<sup>3</sup> Hz. Meanwhile, the mechanical properties and T<sub>g</sub> of films have improved with the addition of an appropriate amount of Al<sub>2</sub>O<sub>3</sub> filler. Compared with neat PI, the maximum increases in the electrical breakdown strength and tensile strength of the composites were at 22.4 and 23.8%, respectively. This study reveals that the performance of PI films as solid dielectric films can be greatly enhanced with incorporating Al<sub>2</sub>O<sub>3</sub> into the PI matrix.

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